

**Search Notes**

Application/Control No.

10/625,567

Examiner

Nhan T. Tran

Applicant(s)/Patent under  
Reexamination

FUNAKOSHI ET AL.

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	241	3/13/2007	NT
358	463	3/15/2007	NT
348	229.1	3/15/2007	NT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/13/2007	NT
348/241-251 (text search - see search history printout)	3/13/2007	NT
382/167 348/273-283, 222.1, 606, 607, 627 (text search - see search history printout)	3/15/2007	NT
text search all databases listed above	3/15/2007	NT
Inventorship search - see search history printout	3/15/2007	NT